

FNK N-Channel Enhancement Mode Power MOSFET

Description

The FNK03N04K uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

V_{DS} =30V,I_D =110A

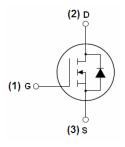
 $R_{DS(ON)}$ <4m Ω @ V_{GS} =10V

 $R_{DS(ON)}$ <5.3m Ω @ V_{GS} =4.5V

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



Schematic diagram



TO-252-2L top view

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
FNK03N04K	FNK03N04K	TO-252-2L	-	-	-

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	VDS	30	V
Gate-Source Voltage	V _G S	±20	V
Drain Current-Continuous	I _D	110	А
Drain Current-Continuous(T _C =100 °C)	I _D (100℃)	88	А
Pulsed Drain Current	I _{DM}	440	А
Maximum Power Dissipation	P _D	130	W
Derating factor		0.87	W/℃
Single pulse avalanche energy (Note 5)	E _{AS}	252	mJ
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 175	$^{\circ}$

FNK-Semiconductor 1/7 Rev.1.1



FNK03N04K

Thermal Characteristic

Thermal Resistance,Junction-to-Case ^(Note 2)	$R_{ heta JC}$	1.15	°C/W	
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Electrical Characteristics (T_C=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics	<u> </u>		•			•
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	30	35	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =30V,V _{GS} =0V -		-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)	<u> </u>		•			•
Gate Threshold Voltage	V _{GS(th)}	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	0.75	1.05	2.0	V
Dunin Course On Otata Desistance	Б	V _{GS} =10V, I _D =10A	-	3.0	4.0	0
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =4.5V, I _D =5A		3.6	5.5	mΩ
Forward Transconductance	g FS	V _{DS} =10V,I _D =20A	32	-	-	S
Dynamic Characteristics (Note4)	<u> </u>		•			•
Input Capacitance	C _{lss}	\/ -45\/\/ -0\/	-	3950	-	PF
Output Capacitance	Coss	V_{DS} =15V, V_{GS} =0V, F=1.0MHz	-	540	-	PF
Reverse Transfer Capacitance	C _{rss}	r=1.0lvlm2	-	480	-	PF
Switching Characteristics (Note 4)	<u> </u>		•			•
Turn-on Delay Time	t _{d(on)}		-	26	-	nS
Turn-on Rise Time	t _r	V_{DD} =15 V , I_D =2 A , R_L =15 Ω	-	24	-	nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =10 V , R_{G} =2.5 Ω	-	91	-	nS
Turn-Off Fall Time	t _f		-	39	-	nS
Total Gate Charge	Qg	\/ -45\/ -20A	-	38		nC
Gate-Source Charge	Q _{gs}	V_{DS} =15V, I_{D} =30A, V_{GS} =10V	-	9		nC
Gate-Drain Charge	Q _{gd}	VGS-1UV	-	13		nC
Drain-Source Diode Characteristics	<u> </u>					
Diode Forward Voltage (Note 3)	V_{SD}	V _{GS} =0V,I _S =10A	-		1.2	V
Diode Forward Current (Note 2)	Is		-	-	150	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF = 40A	-	42	-	nS
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	39	-	nC

Notes:

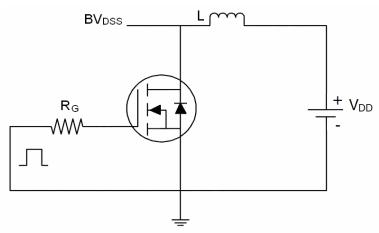
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- **3.** Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production
- **5.** E_{AS} condition : Tj=25 $^{\circ}$ C,V_{DD}=20V,V_G=10V,L=1mH,Rg=25 Ω , I_{AS}=58.5A

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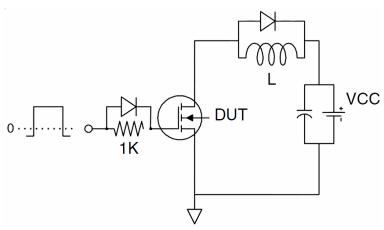


Test circuit

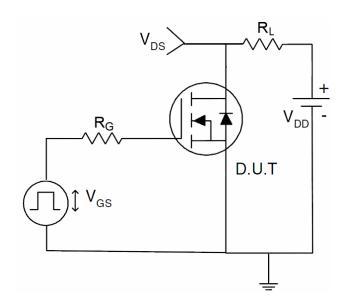
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



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Typical Electrical and Thermal Characteristics (Curves)

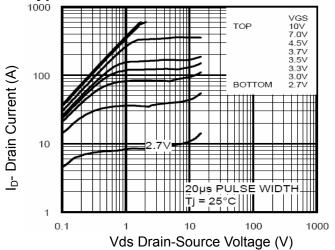


Figure 1 Output Characteristics

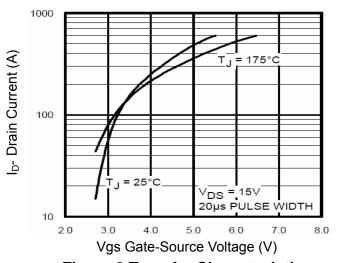


Figure 2 Transfer Characteristics

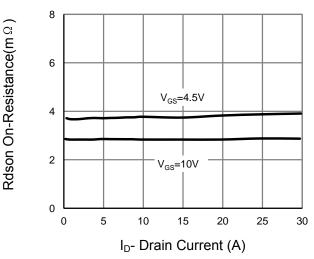


Figure 3 Rdson- Drain Current

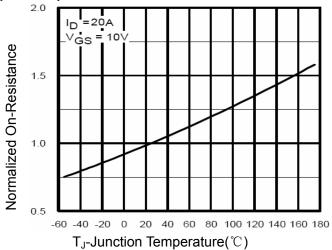


Figure 4 Rdson-JunctionTemperature

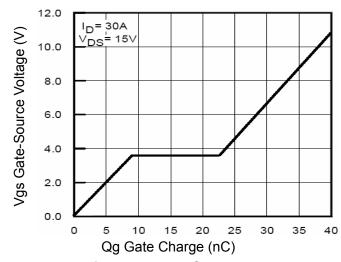


Figure 5 Gate Charge

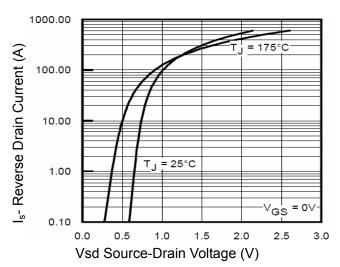


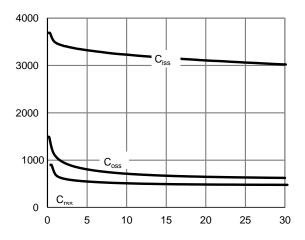
Figure 6 Source- Drain Diode Forward

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C Capacitance (pF)

Ip- Drain Current (A)



Vds Drain-Source Voltage (V)

Figure 7 Capacitance vs Vds

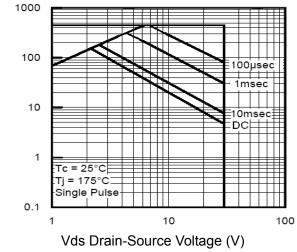


Figure 8 Safe Operation Area

Figure 9 BV_{DSS} vs Junction Temperature

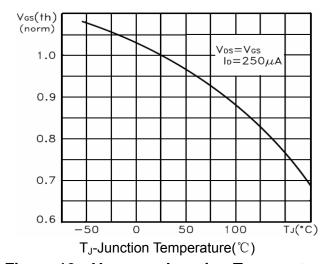


Figure 10 $V_{GS(th)}$ vs Junction Temperature

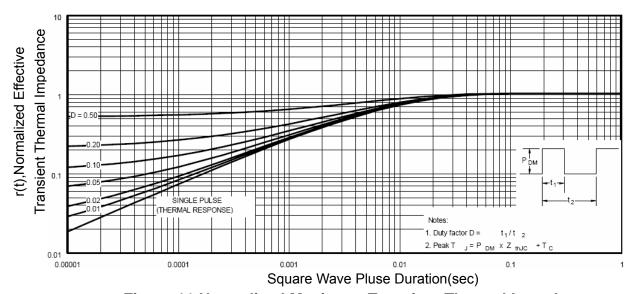
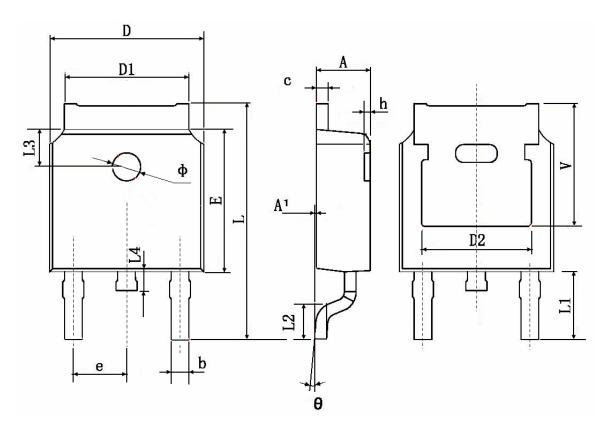


Figure 11 Normalized Maximum Transient Thermal Impedance



TO-252 Package Information



Oli	Dimensions	In Millimeters	Dimensions In Inches			
Symbol	Min.	Max.	Min.	Max.		
Α	2.200	2.400	0.087	0.094		
A1	0.000	0.127	0.000	0.005		
b	0.660	0.860	0.026	0.034		
С	0.460	0.580	0.018	0.023		
D	6.500	6.700	0.256	0.264		
D1	5.100	5.460	0.201	0.215		
D2	4.830	TYP.	0.190 TYP.			
E	6.000	6.200	0.236	0.244		
е	2.186	2.386	0.086	0.094		
L	9.800	10.400	0.386	0.409		
L1	2.900	TYP.	0.114 TYP.			
L2	1.400	1.700	0.055	0.067		
L3	1.600	TYP.	0.063	TYP.		
L4	0.600	1.000	0.024	0.039		
Ф	1.100	1.300	0.043	0.051		
θ	0°	8°	0°	8°		
h	0.000	0.300	0.000	0.012		
V	5.350	TYP.	0.211	1 TYP.		



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